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## **DUAL BUS BUFFER GATE WITH 3-STATE OUTPUTS**

Check for Samples: SN74LVC2G126-EP

#### **FEATURES**

- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max t<sub>pd</sub> of 6.8 ns at 3.3 V
- Low Power Consumption, 10-μA Max I<sub>CC</sub>
- ±24-mA Output Drive at 3.3 V
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   <0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   >2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)

# SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

- Controlled Baseline
- · One Assembly and Test Site
- One Fabrication Site
- Available in Military (–55°C to 125°C)
   Temperature Range
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability

#### DCU PACKAGE (TOP VIEW)

10E∐	1	8	$\Box$ $V_{cc}$
1A ∐	2	7	<b>Ⅲ 20E</b>
2Y 🖂	3	6	<b>□</b> 1Υ
GND $\Box$	4	5	<b>□</b> 2A

#### **DESCRIPTION**

This dual bus buffer gate is designed for 1.65-V to 5.5-V  $V_{CC}$  operation.

The SN74LVC2G126 is a dual bus driver/line driver with 3-state outputs. The outputs are disabled when the associated output-enable (OE) input is low.

To ensure the high-impedance state during power up or power down, OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

### ORDERING INFORMATION(1)

TJ	PACKA	GE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING	VID NUMBER	
-55°C to 125°C	VSSOP - DCU	Tape of 250	CLVC2G126MDCUTEP	CEPR	V62/14604-01XE	

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
- (2) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

## Function Table (Each Buffer)

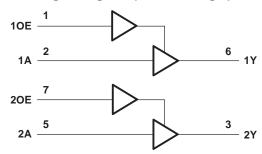
INP	JTS	OUTPUT
OE	Α	Y
Н	Н	Н
Н	L	L
L	Χ	Z



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## **Logic Diagram (Positive Logic)**



## ABSOLUTE MAXIMUM RATINGs(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	6.5	V
VI	Input voltage range <sup>(2)</sup>	nput voltage range <sup>(2)</sup>			
Vo	Voltage range applied to any output in the high-	oltage range applied to any output in the high-impedance or power-off state (2)			
Vo	Voltage range applied to any output in the high	-0.5	V <sub>CC</sub> + 0.5	V	
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GND			±100	mA
TJ	Absolute maximum junction temperature range	-55	150	°C	
T <sub>stg</sub>	Storage temperature range	-65	150	°C	

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) The value of V<sub>CC</sub> is provided in the recommended operating conditions table.

#### THERMAL INFORMATION

		SN74LVC2G126-EP	
	THERMAL METRIC <sup>(1)</sup>	DCU	UNITS
		8 PINS	
$\theta_{JA}$	Junction-to-ambient thermal resistance <sup>(2)</sup>	204.3	
$\theta_{JCtop}$	Junction-to-case (top) thermal resistance (3)	78	
$\theta_{JB}$	Junction-to-board thermal resistance <sup>(4)</sup>	83	°C/W
ΨЈТ	Junction-to-top characterization parameter <sup>(5)</sup>	7.6	C/VV
ΨЈВ	Junction-to-board characterization parameter <sup>(6)</sup>	82.6	
$\theta_{JCbot}$	Junction-to-case (bottom) thermal resistance <sup>(7)</sup>	N/A	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ<sub>JT</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ<sub>JB</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

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## **RECOMMENDED OPERATING CONDITIONS<sup>(1)</sup>**

			MIN	MAX	UNIT			
.,	Owner have the me	Operating	1.65	5.5	V			
$V_{CC}$	Supply voltage	Data retention only	1.5		V			
		V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>					
.,	High lavel input values	V <sub>CC</sub> = 2.3 V to 2.7 V	1.7		V			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	2		V			
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0.7 × V <sub>CC</sub>					
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		$0.35 \times V_{CC}$				
.,	Law law alian et walta a a	V <sub>CC</sub> = 2.3 V to 2.7 V		0.7				
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		0.8	V			
		V <sub>CC</sub> = 4.5 V to 5.5 V		0.3 × V <sub>CC</sub>	1			
VI	Input voltage		0	5.5	V			
.,	Outrot valta a	High or low state	0	$V_{CC}$	V			
Vo	Output voltage	3-state	0	5.5	v			
		V <sub>CC</sub> = 1.65 V		-4				
		V <sub>CC</sub> = 2.3 V		-8				
$I_{OH}$	High-level output current	V - 2 V		-16	mA			
		V <sub>CC</sub> = 3 V		-24				
		V <sub>CC</sub> = 4.5 V		-32				
		V <sub>CC</sub> = 1.65 V		4				
		V <sub>CC</sub> = 2.3 V		8				
$I_{OL}$	Low-level output current	V <sub>CC</sub> = 3 V		16	mA			
		V <sub>CC</sub> = 3 V		24				
		V <sub>CC</sub> = 4.5 V		32				
		$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$	20		ns/V			
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	10					
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$		5				
TJ	Operating virtual junction temperature		-55	125	°C			

<sup>(1)</sup> All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

Product Folder Links: SN74LVC2G126-EP



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## **ELECTRICAL CHARACTERISTICS**

These specifications apply for  $-55^{\circ}\text{C} \le \text{T}_{\text{J}} \le 125^{\circ}\text{C}$  (unless otherwise noted)

Р	ARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP <sup>(1)</sup>	MAX	UNIT	
		$I_{OH} = -100 \ \mu A$	1.65 V to 5.5 V	$V_{CC} - 0.1$				
		$I_{OH} = -4 \text{ mA}$	1.65 V	1.2				
.,		$I_{OH} = -8 \text{ mA}$	2.3 V	1.9			V	
V <sub>OH</sub>		$I_{OH} = -16 \text{ mA}$	3 V	2.4			V	
		$I_{OH} = -24 \text{ mA}$	3 V	2.3				
		$I_{OH} = -32 \text{ mA}$	4.5 V	3.8				
		I <sub>OL</sub> = 100 μA	1.65 V to 5.5 V			0.1		
		I <sub>OL</sub> = 4 mA	1.65 V			0.45		
V		I <sub>OL</sub> = 8 mA	2.3 V			0.3	V	
V <sub>OL</sub>		I <sub>OL</sub> = 16 mA	3 V		0.4			
		I <sub>OL</sub> = 24 mA	3 V			0.55		
		I <sub>OL</sub> = 32 mA	4.5 V			0.55		
I <sub>I</sub>	A or OE inputs	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V			±5	μΑ	
I <sub>off</sub>		$V_I$ or $V_O = 5.5 \text{ V}$	0			±10	μA	
I <sub>OZ</sub>		$V_{O} = 0 \text{ to } 5.5 \text{ V}$	3.6 V			10	μA	
I <sub>CC</sub>		$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V			10	μA	
$\Delta I_{CC}$		One input at $V_{CC}$ – 0.6 V, Other inputs at $V_{CC}$ or GND	3 V to 5.5 V			500	μA	
	Data inputs				3.5			
Cı	Control inputs	$V_I = V_{CC}$ or GND	3.3 V		4		pF	
Co	<u> </u>	$V_O = V_{CC}$ or GND	3.3 V		6.5		pF	

<sup>(1)</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_J$  = 25°C.

### **SWITCHING CHARACTERISTICS**

These specifications apply for  $-55^{\circ}\text{C} \le T_{J} \le 125^{\circ}\text{C}$  (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	FROM TO (INPUT) (OUTPUT)		V <sub>CC</sub> = 1.8 V ± 0.15 V V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT	
	(INFOT)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>pd</sub>	A	Υ	3.5	15.2	1.7	8.6	1.4	6.8	1	5.5	ns
t <sub>en</sub>	OE	Υ	3.5	15.2	1.7	8.6	1.5	6.8	1	5.5	ns
t <sub>dis</sub>	OE	Υ	1.7	12.6	1	5.7	1	4.5	0.1	3.3	ns

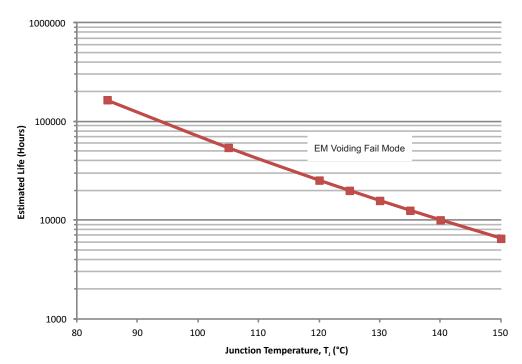
## **OPERATING CHARACTERISTICS**

 $T_J = 25^{\circ}$ 

	PARAMETER	₹	TEST CONDITIONS	V <sub>CC</sub> = 1.8 V TYP	V <sub>CC</sub> = 2.5 V TYP	V <sub>CC</sub> = 3.3 V TYP	V <sub>CC</sub> = 5 V TYP	UNIT
_	Power dissipation capacitance	Outputs enabled	f = 10 MHz	19	19	20	22	pF
$C_{pd}$		Outputs disabled	I = IU WINZ	2	2	2	3	

Product Folder Links: SN74LVC2G126-EP

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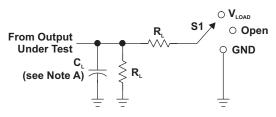
- (1) See datasheet for absolute maximum and minimum recommended operating conditions.
- (2) Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).
- (3) Enhanced plastic product disclaimer applies.

Figure 1. SN74LVC2G126-EP Operating Life Derating Chart

**ISTRUMENTS** 



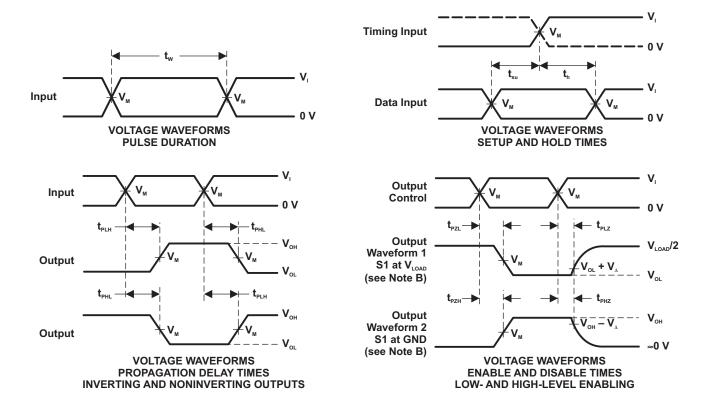
#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
$t_{_{\mathrm{PLZ}}}/t_{_{\mathrm{PZL}}}$	<b>V</b> <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

LOAD CIRCUIT

,,	INI	PUTS	.,	.,		R	
V <sub>cc</sub>	V <sub>1</sub> t <sub>r</sub> /t <sub>r</sub> V <sub>M</sub> V <sub>LOAD</sub>		C <sub>L</sub>	R <sub>⊾</sub>	<b>V</b> <sub>Δ</sub>		
1.8 V ± 0.15 V	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	<b>1 k</b> Ω	0.15 V
$2.5~\textrm{V}~\pm~0.2~\textrm{V}$	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	500 Ω	0.15 V
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
5 V ± 0.5 V	V <sub>cc</sub>	≤2.5 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	50 pF	500 Ω	0.3 V



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_o$  = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{\mbox{\tiny PLZ}}$  and  $\dot{t}_{\mbox{\tiny PHZ}}$  are the same as  $t_{\mbox{\tiny dis}}.$
- F.  $t_{\mbox{\tiny PZL}}$  and  $t_{\mbox{\tiny PZH}}$  are the same as  $t_{\mbox{\tiny en}}.$
- G.  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  are the same as  $t_{\text{pd}}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms

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## PACKAGE OPTION ADDENDUM

17-Aug-2015

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CLVC2G126MDCUTEP	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CEPR	Samples
V62/14604-01XE	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CEPR	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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## **PACKAGE OPTION ADDENDUM**

17-Aug-2015

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74LVC2G126-EP:

● Catalog: SN74LVC2G126

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

## **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CLVC2G126MDCUTEP	VSSOP	DCU	8	250	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CLVC2G126MDCUTEP	VSSOP	DCU	8	250	202.0	201.0	28.0	

## DCU (R-PDSO-G8)

## PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



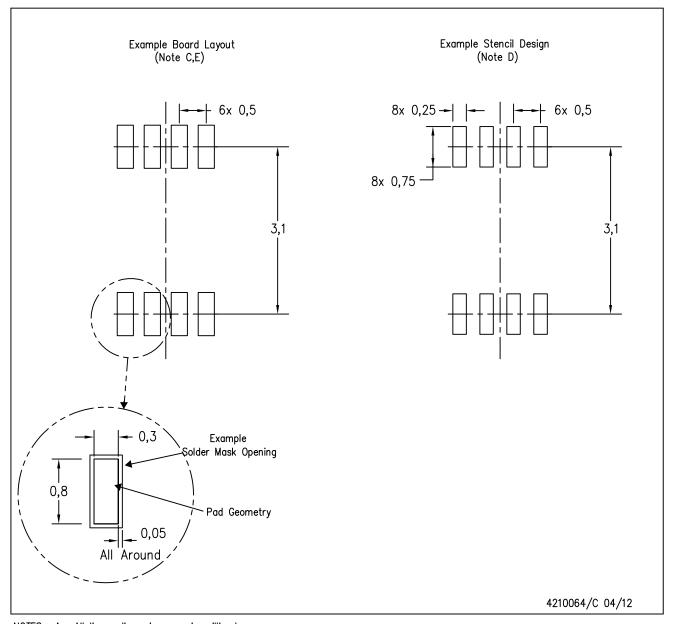
NOTES:

- A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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